### features

- Dual-Input, Single-Output MOSFET Switch With No Reverse Current Flow (No Parasitic Diodes)
- IN1...250-mΩ, 500-mA N-Channel;
   14-μA Supply Current
- IN2...1.3-Ω, 100-mA P-Channel;
   0.75-μA Supply Current (V<sub>AUX</sub> Mode)
- Advanced Switch Control Logic
- CMOS and TTL Compatible Enable Input
- Controlled Rise, Fall, and Transition Times
- 2.7 V to 4 V Operating Range
- SOT-23-5 and SOIC-8 Package
- −40°C to 70°C Ambient Temperature Range
- 2-kV Human Body Model, 750-V Charged Device Model, 200-V Machine-Model ESD Protection

### typical applications

- Notebook and Desktop PCs
- Cell phone, Palmtops, and PDAs
- Battery Management

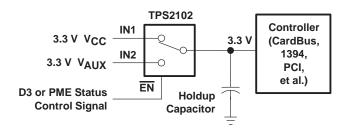


Figure 1. Typical Dual-Input Single-Output
Application

### description

The TPS2102 and TPS2103 are dual-input, single-output power switches designed to provide uninterrupted output voltage when transitioning between two independent power supplies. Both devices combine one n-channel (250 m $\Omega$ ) and one p-channel (1.3  $\Omega$ ) MOSFET with a single output. The p-channel MOSFET (IN2) is used with auxiliary power supplies that deliver lower current for standby modes. The n-channel MOSFET (IN1) is used with a main power supply that delivers higher current required for normal operation. Low on-resistance makes the n-channel the ideal path for higher main supply current when power-supply regulation and system voltage drops are critical. When using the p-channel MOSFET, quiescent current is reduced to 0.75  $\mu$ A to decrease the demand on the standby power supply. The MOSFETs in the TPS2102 and TPS2103 do not have the parasitic diodes, typically found in discrete MOSFETs, thereby preventing back-flow current when the switch is off.

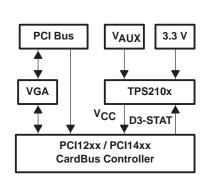
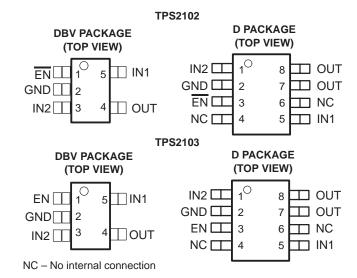


Figure 2. VAUX CardBus Implementation





Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



### Selection Guide, V<sub>AUX</sub> Power-Distribution Switches

DEVICE	ENABLE	OPERATING VOLTAGE RANGE (V)	MAXIMUM INPUT CURRENT, IN1 (mA)	MAXIMUM INPUT CURRENT, IN2 (mA)	AMBIENT TEMPERATURE RANGE (°C)
TPS2100	EN	2.7 to 4	500	10	-40 to 70
TPS2101	EN	2.7 to 4	500	10	-40 to 70
TPS2102	EN	2.7 to 4	500	100	-40 to 70
TPS2103	EN	2.7 to 4	500	100	-40 to 70
TPS2104	EN	2.7 to 5.5	500	100	-40 to 85
TPS2105	EN	2.7 to 5.5	500	100	-40 to 85

### **AVAILABLE OPTIONS FOR TPS2102, TPS2103**

			PACKAGED DE	VICES
T <sub>A</sub> DEVICE		ENABLE	SOT-23-5 (DBV) <sup>†</sup>	SOIC-8 (D)
-40°C to 70°C	TPS2102	EN	TSP2102DBV <sup>†</sup>	TPS2102D
	TPS2103	EN	TPS2103DBV <sup>†</sup>	TPS2103D

Both packages are available left-end taped and reeled. Add an R suffix to the D device type (e.g., TPS2103DR).

### **Function Tables**

TPS2102									
VIN1	VIN2	EN	OUT						
0 V	0 V	XX	GND						
0 V	3.3 V	L	GND						
3.3 V	0 V	L	VIN1						
3.3 V	3.3 V	L	VIN1						
0 V	3.3 V	Н	VIN2						
3.3 V	0 V	Н	VIN2						
3.3 V	3.3 V	Н	VIN2						

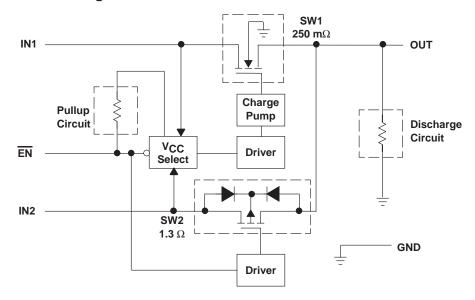
XX = don't care

	TPS2103									
VIN1	VIN2	EN	OUT							
0 V	0 V	XX	GND							
0 V	3.3 V	Н	GND							
3.3 V	0 V	Н	VIN1							
3.3 V	3.3 V	Н	VIN1							
0 V	3.3 V	L	VIN2							
3.3 V	0 V	L	VIN2							
3.3 V	3.3 V	L	VIN2							

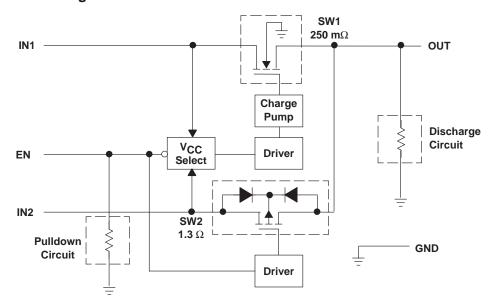


TAdd T (e.g., TPS2102DBVT) to indicate tape and reel at order quantity of 250 parts. Add R (e.g., TPS2102DBVR) to indicate tape and reel at order quantity of 3000 parts.

### TPS2102 functional block diagram



### TPS2103 functional block diagram



### **Terminal Functions**

	TERMINAL					
NO. NAME TPS2102 TPS2103		N	0.			DESCRIPTION
		2103	1/0	DESCRIPTION		
	DBV	D	DBV	D		
EN			1	3	ı	Active-high enable for IN1-OUT switch
EN	1	3			I	Active-low enable for IN1-OUT switch
GND	2	2	2	2	I	Ground
IN1 <sup>†</sup>	5	5	5	5	I	Main Input voltage, NMOS drain (250 mΩ), require 0.22 μF bypass
IN2†	3	1	3	1	ı	Auxilliary input voltage, PMOS drain (1.3 $\Omega$ ), require 0.22 $\mu$ F bypass
OUT	4	7, 8	4	7, 8	0	Power switch output
NC		4, 6		4, 6		No connection

<sup>†</sup> Unused INx should not be grounded.

### detailed description

### power switches

### n-channel MOSFET

The IN1-OUT n-channel MOSFET power switch has a typical on-resistance of 250 m $\Omega$  at 3.3-V input voltage, and is configured as a high-side switch.

### p-channel MOSFET

The IN2-OUT p-channel MOSFET power switch has a typical on-resistance of 1.3  $\Omega$  at 3.3-V input voltage and is configured as a high-side switch. When operating, the p-channel MOSFET quiescent current is reduced to typically 0.75  $\mu$ A.

### charge pump

An internal charge pump supplies power to the driver circuit and provides the necessary voltage to pull the gate of the MOSFET above the source. The charge pump operates from input voltages as low as 2.7 V and requires very little supply current.

### driver

The driver controls the gate voltage of the IN1-OUT and IN2-OUT power switches. To limit large current surges and reduce the associated electromagnetic interference (EMI) produced, the drivers incorporate circuitry that controls the rise times and fall times of the output voltage.

### enable

The logic enable will turn on the IN2-OUT power switch when a logic high is present on  $\overline{\text{EN}}$  (TPS2102) or logic low is present on EN (TPS2103). A logic low input on  $\overline{\text{EN}}$  (TPS2102) or logic high on EN (TPS2103) restores bias to the drive and control circuits and turns on the IN1-OUT power switch. The enable input is compatible with both TTL and CMOS logic levels.

### the V<sub>AUX</sub> application for CardBus controllers

The PC Card specification requires the support of  $V_{AUX}$  to the CardBus controller as well as to the PC Card sockets. Both are 3.3-V requirements; however the CardBus controller's current demand from the  $V_{AUX}$  supply is limited to 10  $\mu$ A, whereas the PC Card may consume as much as 200 mA. In either implementation, if support of a wake-up event is required, the controller and the socket will transition from the 3.3-V  $V_{CC}$  rail to the 3.3-V  $V_{AUX}$  rail when the equipment moves into a low power mode such as D3. The transition from  $V_{CC}$  to  $V_{AUX}$  needs to be seamless in order to maintain all memory and register information in the system. If  $V_{AUX}$  is not supported, the system will lose all register information when it transitions to the D3 state.



### absolute maximum ratings over operating free-air temperature (unless otherwise noted)†

Input voltage range, V <sub>I(IN1)</sub> (see Note 1)	0.3 V to 5 V
Input voltage range, V <sub>I(IN2)</sub> (see Note 1)	0.3 V to 5 V
Input voltage range, V <sub>I</sub> at EN or EN (see Note 1)	0.3 V to 5 V
Output voltage range, V <sub>O</sub> (see Note 1)	0.3 V to 5 V
Continuous output current, I <sub>O(IN1)</sub>	700 mA
Continuous output current, I <sub>O(IN2)</sub>	140 mA
Continuous total power dissipation	
Operating virtual junction temperature range, T <sub>J</sub>	–40°C to 85°C
Storage temperature range, T <sub>stq</sub>	65°C to 150°C
Lead temperature soldering 1,6 mm (1/16 inch) from case for 10	0 seconds 260°C
Electrostatic discharge (ESD) protection: Human body model	2 kV
Machine model	200 V
Charged device mode	el

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: All voltages are with respect to GND.

### **DISSIPATION RATING TABLE**

PACKAGE	T <sub>A</sub> < 25°C POWER RATING	DERATING FACTOR ABOVE T <sub>A</sub> = 25°C	T <sub>A</sub> = 70°C POWER RATING	T <sub>A</sub> = 85°C POWER RATING
DBV	309 mW	3.1 mW/°C	170 mW	123 mW
D	568 mW	5.7 mW/°C	313 mW	227 mW

### recommended operating conditions

	MII	N MAX	UNIT
Input voltage, VI(INx)	2.	7 4	V
Input voltage, V <sub>I</sub> at EN and EN		) 4	V
Continuous output current, IO(IN1)		500	mA
Continuous output current, IO(IN2)		100‡	mA
Operating virtual junction temperature, T <sub>J</sub>	-4	0 85	°C

<sup>&</sup>lt;sup>‡</sup> The device can deliver up to 220 mA at I<sub>O(IN2)</sub>. However, operation at the higher current levels will result in greater voltage drop across the device, and greater voltage droop when switching between IN1 and IN2.

# electrical characteristics over recommended operating junction temperature range, $V_{I(IN1)} = V_{(IN2)} = 3.3 \text{ V}$ , $I_O = \text{rated current (unless otherwise noted)}$

### power switch

perior emiliar						
PARAMETER	TEST CONDITIONS†	MIN	TYP	MAX	UNIT	
	IN1-OUT	T <sub>J</sub> = 25°C		250		mΩ
rps(on) On-state resistance	1111-001	T <sub>J</sub> = 85°C		300	375	11122
rDS(on) On-state resistance	IN2-OUT	T <sub>J</sub> = 25°C		1.3		
	IN2-001	T <sub>J</sub> = 85°C		1.5	2.1	Ω

<sup>†</sup> Pulse-testing techniques maintain junction temperature close to ambient termperature; thermal effects must be taken into account separately.



# TPS2102, TPS2103 V<sub>AUX</sub> POWER-DISTRIBUTION SWITCHES

SLVS234A - SEPTEMBER 1999 - REVISED APRIL 2000

# electrical characteristics over recommended operating junction temperature range, $V_{I(IN1)} = V_{(IN2)} = 3.3 \text{ V}$ , $I_O = \text{rated current (unless otherwise noted) (continued)}$

### enable input (EN and EN)

PARAMETER			TEST CONDITIONS			MAX	UNIT
VIH	High-level input voltage	2.7 V ≤ V <sub>I(IN</sub>	2.7 V ≤ V <sub>I(INx)</sub> ≤ 4 V				V
VIL	Low-level input voltage	2.7 V ≤ V <sub>I(IN</sub>	$2.7 \text{ V} \le \text{V}_{\text{I(INx)}} \le 4 \text{ V}$			0.8	V
ī	Input current	TPS2102	$\overline{EN} = 0 \text{ V or } \overline{EN} = V_{I(INX)}$	-0.5		0.5	μΑ
l''		TPS2103	$EN = 0 V \text{ or } EN = V_{I(INx)}$	-0.5		0.5	μΑ

### supply current

	PARAMETER	TEST CONDITIONS			MIN	TYP	MAX	UNIT	
0			EN = H,	T <sub>J</sub> = 25°C		0.75		μΑ	
		TPS2102	IN2 selected	$-40^{\circ}C \le T_{J} \le 85^{\circ}C$			1.5	μΑ	
		1732102	$\overline{EN} = L,$	T <sub>J</sub> = 25°C		14		μΑ	
	Supply current		IN1 selected	$-40^{\circ}\text{C} \le \text{T}_{\text{J}} \le 85^{\circ}\text{C}$			24		
"	Зирріу сипені	TPS2103	EN = L, IN2 selected	T <sub>J</sub> = 25°C		0.75		μА	
				$-40^{\circ}C \le T_{J} \le 85^{\circ}C$			1.5	μΑ	
			EN = H, IN1 selected	T <sub>J</sub> = 25°C		14			
				$-40^{\circ}\text{C} \le \text{T}_{\text{J}} \le 85^{\circ}\text{C}$			24	μΑ	

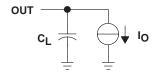
### switching characteristics, $T_J = 25^{\circ}C$ , $V_{I(IN1)} = V_{I(IN2)} = 3.3 \text{ V (unless otherwise noted)}^{\dagger}$

	PARAMETER		TE	ST CONDITIO	ns†	MIN TYP	MAX	UNIT	
				$C_L = 1 \mu F$ ,	I <sub>L</sub> = 500 mA	440			
		IN1-OUT	$V_{I(IN2)} = 0$	$C_L = 10 \mu F$ ,	I <sub>L</sub> = 500 mA	440			
t <sub>r</sub> Output rise time	Output rice time			$C_L = 1 \mu F$ ,	I <sub>L</sub> = 100 mA	370			
			$C_L = 1 \mu F$ ,	I <sub>L</sub> = 100 mA	4.6		μs		
		IN2-OUT	$V_{I(IN1)} = 0$	$C_L = 10 \mu F$ ,	I <sub>L</sub> = 100 mA	50			
				$C_L = 1 \mu F$ ,	I <sub>L</sub> = 10 mA	4.6			
		IN1-OUT	V <sub>I(IN2)</sub> = 0	$C_L = 1 \mu F$ ,	I <sub>L</sub> = 500 mA	5		με	
				$C_L = 10 \mu F$ ,	$I_L = 500 \text{ mA}$	100			
t <sub>f</sub>	Output fall time			$C_L = 1 \mu F$ ,	$I_L = 100 \text{ mA}$	13			
14	Output fair time		V <sub>I(IN1)</sub> = 0	$C_L = 1 \mu F$ ,	$I_L = 100 \text{ mA}$	68			
		IN2-OUT		$C_L = 10 \mu F$ ,	I <sub>L</sub> = 100 mA	680			
				$C_L = 1 \mu F$ ,	I <sub>L</sub> = 10 mA	720			
tou	Propagation delay time, low-to-high output	IN1-OUT	$V_{I(IN2)} = 0$	C. = 10E	lı = 100 mA	80			
tPLH	Propagation delay time, low-to-night output	IN2-OUT	$V_{I(IN1)} = 0$	ο <u>ι</u> – 10 μι-,	$C_L = 10 \mu\text{F},  I_L = 100 \text{mA}$			μs	
tou	Propagation delay time, high-to-low output	IN1-OUT	$V_{I(IN2)} = 0$	C <sub>I</sub> = 10 μF,	I <sub>I</sub> = 100 mA	3			
<sup>t</sup> PHL		IN2-OUT	$V_{I(IN1)} = 0$		IL = 100 IIIA	40		μs	

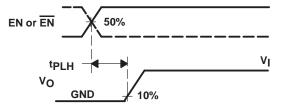
<sup>†</sup> All timing parameters refer to Figure 3.

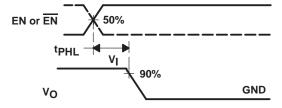


### PARAMETER MEASUREMENT INFORMATION



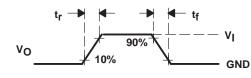
**LOAD CIRCUIT** 



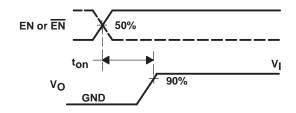


Propagation Delay Time, Low-to-High-Level Output

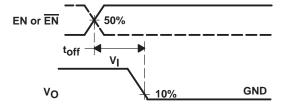
Propagation Delay Time, High-to-Low-Level Output



Rise/Fall Time



**Turn-on Transition Time** 



**Turn-off Transition Time** 

**WAVEFORMS** 

Figure 3. Test Circuit and Voltage Waveforms

### Table of Timing Diagrams†

	FIGURE
Propagation Delay and Rise Time With 0.1-μF Load, IN1	4
Propagation Delay and Rise Time With 0.1-μF Load, IN2	5
Propagation Delay and Fall Time With 0.1-μF Load, IN1	6
Propagation Delay and Fall Time With 0.1-μF Load, IN2	7
Propagation Delay and Rise Time With 1-μF Load, IN1	8
Propagation Delay and Rise Time With 1-μF Load, IN2	9
Propagation Delay and Fall Time With 1-μF Load, IN1	
Propagation Delay and Fall Time With 1-μF Load, IN2	11

 $<sup>^{\</sup>dagger}$  Waveforms shown in Figures 4–11 refer to TPS2102 at T<sub>J</sub> = 25°C



### PARAMETER MEASUREMENT INFORMATION

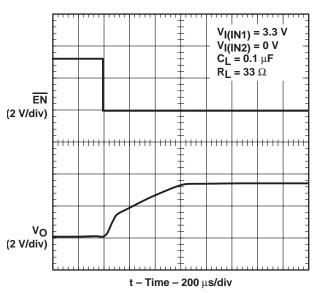


Figure 4. Propagation Delay and Rise Time With 0.1-μF Load, IN1 Turnon

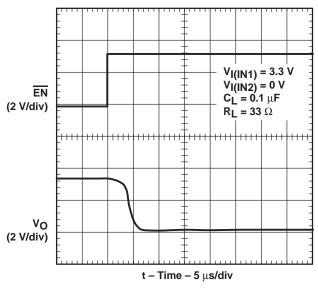


Figure 6. Propagation Delay and Fall Time With 0.1-μF Load, IN1 Turnoff

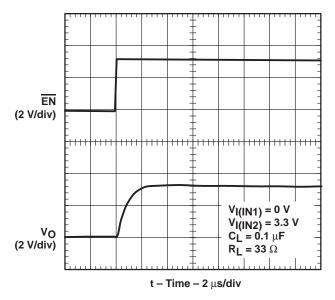


Figure 5. Propagation Delay and Fall Time With 0.1-μF Load, IN2 Turnon

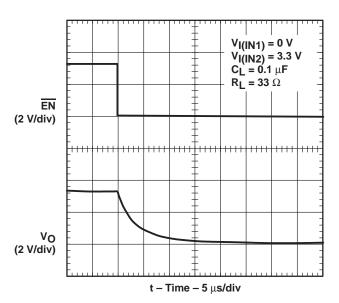


Figure 7. Propagation Delay and Fall Time With 0.1-μF Load, IN2 Turnoff



### PARAMETER MEASUREMENT INFORMATION

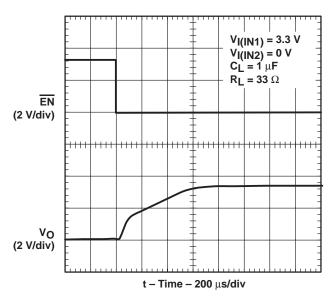


Figure 8. Propagation Delay and Rise Time With 1-μF Load, IN1 Turnon

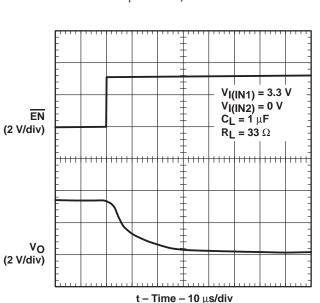


Figure 10. Propagation Delay and Fall Time With 1-μF Load, IN1 Turnoff

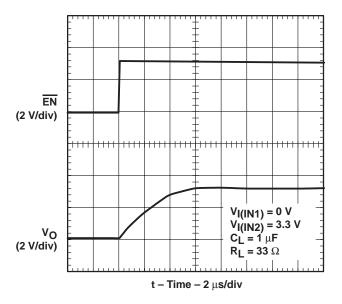


Figure 9. Propagation Delay and Rise Time With 1-μF Load, IN2 Turnon

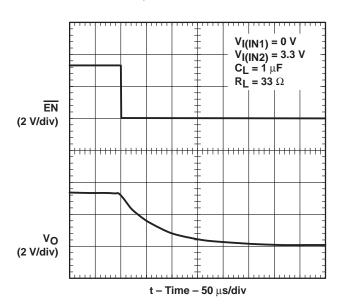


Figure 11. Propagation Delay and Fall Time With 1-μF Load, IN2 Turnoff

### **Table of Graphs**

		FIGURE
IN1 Switch Rise Time	vs Output Current	12
IN2 Switch Fall Time	vs Output Current	13
IN1 Switch Fall Time	vs Output Current	14
IN2 Switch Fall Time	vs Output Current	15
Output Voltage Droop	vs Output Current When Output Is Switched From IN2 to IN1	16
Inrush Current	vs Output Capacitance	17
IN1 Supply Current	vs Junction Temperature (IN1 Enabled)	18
IN1 Supply Current	vs Junction Temperature (IN1 Disabled)	19
IN2 Supply Current	vs Junction Temperature (IN2 Enabled)	20
IN2 Supply Current	vs Junction Temperature (IN2 Disabled)	21
IN1-OUT On-State Resistance	vs Junction Temperature	22
IN2-OUT On-State Resistance	vs Junction Temperature	23

## IN1 SWITCH RISE TIME

### OUTPUT CURRENT

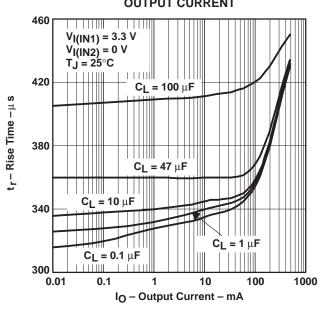
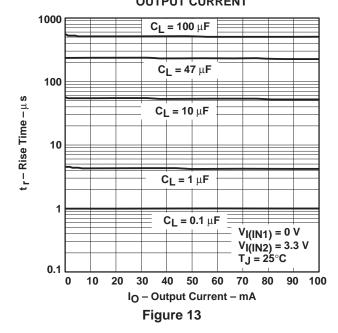
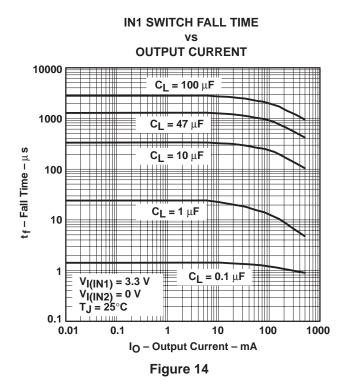
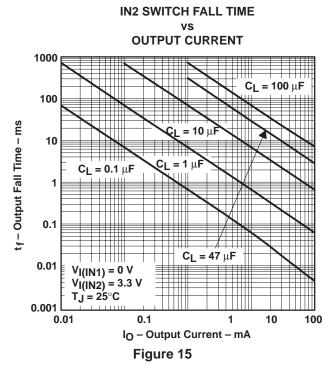


Figure 12

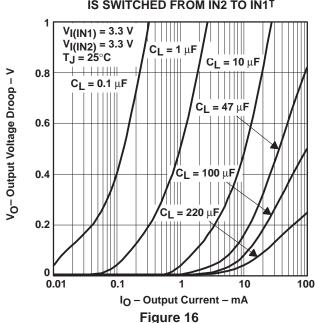
# IN2 SWITCH RISE TIME vs OUTPUT CURRENT



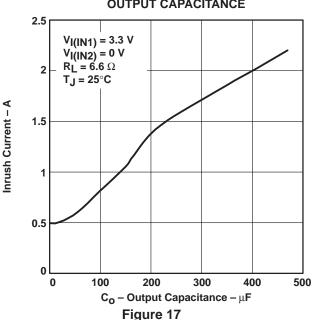




# OUTPUT VOLTAGE DROOP VS OUTPUT CURRENT WHEN OUTPUT IS SWITCHED FROM IN2 TO IN1<sup>†</sup>

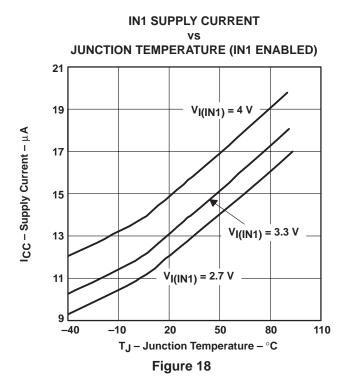


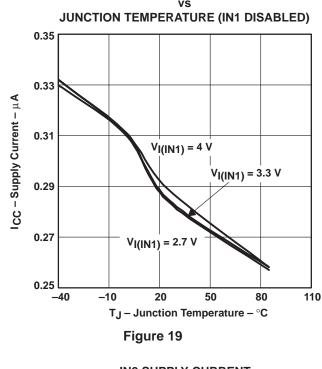
# INRUSH CURRENT vs OUTPUT CAPACITANCE



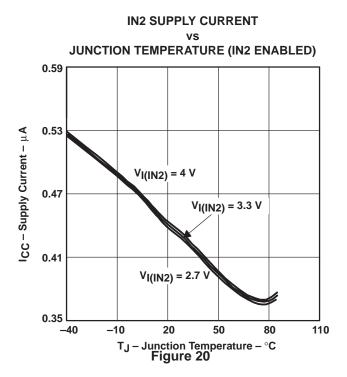
<sup>†</sup> If switching from IN1 to IN2, the voltage droop is much smaller. Therefore, the load capacitance should be chosen according to the curves in Figure 16.

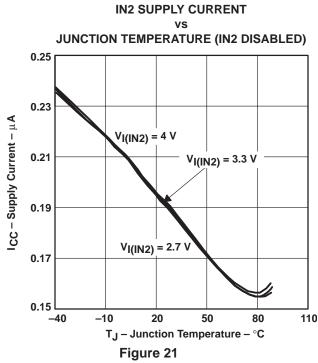


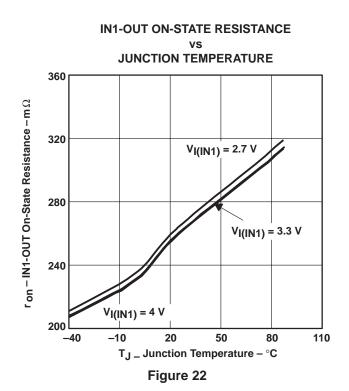




**IN1 SUPPLY CURRENT** 







# IN2-OUT ON-STATE RESISTANCE VS JUNCTION TEMPERATURE 2.5 VI(IN2) = 2.7 V VI(IN2) = 3.3 V VI(IN2) = 4 V TJ – Junction Temperature – °C

Figure 23

### **APPLICATION INFORMATION**

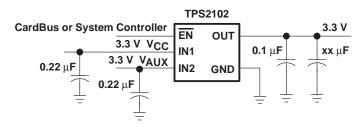


Figure 24. Typical Application

### power-supply considerations

A 0.22- $\mu F$  ceramic bypass capacitor between IN and GND, close to the device is recommended. The output capacitor should be chosen based on the size of the load during the transition of the switch. A 220- $\mu F$  capacitor is recommended for 100 mA loads. Typical output capacitors (xx  $\mu F$ , shown in Figure 24) required for a given load can be determined from Figure 16 which shows the output voltage droop when output is switched from IN2 to IN1. The output voltage droop is insignificant when output is switched from IN1 to IN2. Additionally, bypassing the output with a 0.1- $\mu F$  ceramic capacitor improves the immunity of the device to short-circuit transients.



### APPLICATION INFORMATION

### power supply considerations (continued)

### switch transition

The n-channel MOSFET on IN1 uses a charge pump to create the gate-drive voltage, which gives the IN1 switch a rise time of approximately 0.5 ms. The p-channel MOSFET on IN2 has a simpler drive circuit that allows a rise time of approximately  $5\,\mu s$ . Because the device has two switches and a single enable pin, these rise times are seen as transition times, from IN1 to IN2, or IN2 to IN1, by the output. The controlled transition times help limit the surge currents seen by the power supply during switching.

### thermal protection

Thermal protection provided on the IN1 switch prevents damage to the IC when heavy-overload or short-circuit faults are present for extended periods of time. The increased dissipation causes the junction temperature to rise to dangerously high levels. The protection circuit senses the junction temperature of the switch and shuts it off at approximately  $145^{\circ}$ C (T<sub>J</sub>). The switch remains off until the junction temperature has dropped approximately  $10^{\circ}$ C. The switch continues to cycle in this manner until the load fault or input power is removed.

### undervoltage lockout

An undervoltage lockout function is provided to ensure that the power switch is in the off state at power-up. Whenever the input voltage falls below approximately 2 V, the power switch quickly turns off. This function facilitates the design of hot-insertion systems that may not have the capability to turn off the power switch before input power is removed. Upon reinsertion, the power switch will be turned on with a controlled rise time to reduce EMI and voltage overshoots.

### power dissipation and junction temperature

The low on-resistance on the n-channel MOSFET allows small surface-mount packages, such as SOIC, to pass large currents. The thermal resistances of these packages are high compared to that of power packages; it is good design practice to check power dissipation and junction temperature. First, find  $r_{on}$  at the input voltage, and operating temperature. As an initial estimate, use the highest operating ambient temperature of interest and read  $r_{on}$  from Figure 22 or Figure 23. Next calculate the power dissipation using:

$$P_D = r_{on} \times I^2$$

Finally, calculate the junction temperature:

$$T_J = P_D \times R_{\theta JA} + T_A$$

Where:

 $T_A$  = Ambient temperature

 $R_{\theta,IA}$  = Thermal resistance

Compare the calculated junction temperature with the initial estimate. If they do not agree within a few degrees, repeat the calculation using the calculated value as the new estimate. Two or three iterations are generally sufficient to obtain a reasonable answer.

### **ESD** protection

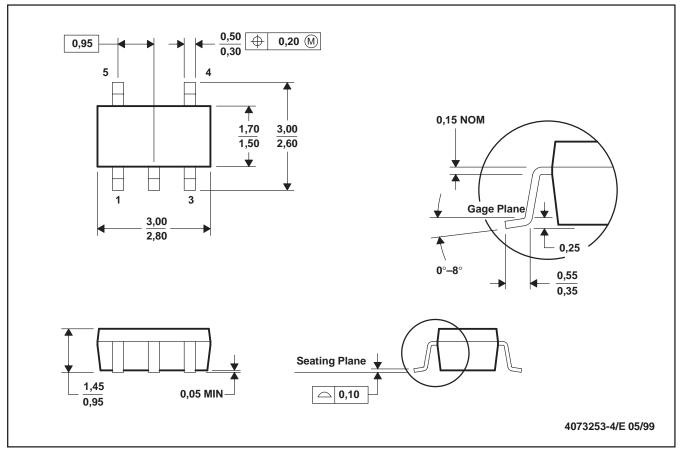
All TPS2102 and TPS2103 terminals incorporate ESD-protection circuitry designed to withstand a 2-kV human-body-model, 750-V CDM, and 200-V machine-model discharge as defined in MIL-STD-883C.



### **MECHANICAL DATA**

### DBV (R-PDSO-G5)

### PLASTIC SMALL-OUTLINE



NOTES: A. All linear dimensions are in millimeters.

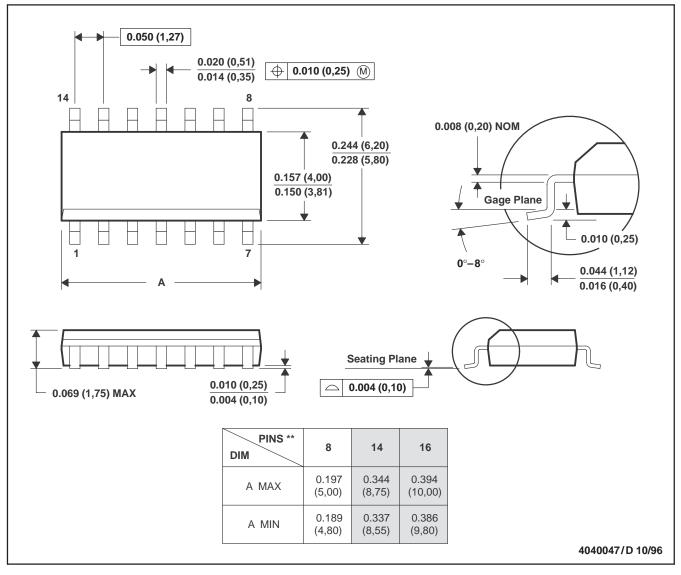
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion.
- D. Falls within JEDEC MO-178

### **MECHANICAL DATA**

### D (R-PDSO-G\*\*)

### 14 PINS SHOWN

### PLASTIC SMALL-OUTLINE PACKAGE



NOTES: A. All linear dimensions are in inches (millimeters).

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion, not to exceed 0.006 (0,15).

D. Falls within JEDEC MS-012

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